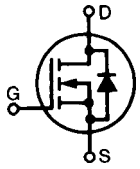
IXYS

HiPerFET™ Power MOSFETs

IXFH 13N50
IXFM 13N50

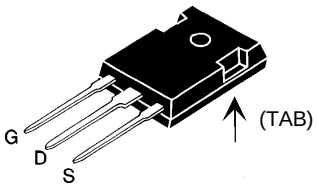
V_{DSS} = 500 V
$I_{D (cont)}$ = 13 A
$R_{DS(on)}$ = 0.4 Ω
t_{rr} ≤ 250 ns

N-Channel Enhancement Mode
High dv/dt, Low t_{rr}, HDMOS™ Family

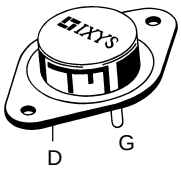


Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	T_J = 25°C to 150°C	500	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1 MΩ	500	V
V_{GS}	Continuous	±20	V
V_{GSM}	Transient	±30	V
I_{D25}	T_C = 25°C	13	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	52	A
I_{AR}	T_C = 25°C	13	A
E_{AR}	T_C = 25°C	18	mJ
dv/dt	$I_S \le I_{DM}$, di/dt ≤ 100 A/μs, $V_{DD} \le V_{DSS}$, $T_J \le 150°C$, R_G = 2 Ω	5	V/ns
P_D	T_C = 25°C	180	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C
M_d	Mounting torque	1.13/10	Nm/lb.in.
Weight		TO-204 = 18 g, TO-247 = 6 g	

TO-247 AD (IXFH)



TO-204 AA (IXFM)



G = Gate, D = Drain,
S = Source, TAB = Drain

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
V_{DSS}	V_{GS} = 0 V, I_D = 250 μA	500			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 2.5 mA	2		4	V
I_{GSS}	V_{GS} = ±20 V_{DC}, V_{DS} = 0			±100	nA
I_{DSS}	$V_{DS} = 0.8 \cdot V_{DSS}$, V_{GS} = 0 V; T_J = 25°C			200	μA
				1	mA
					T_J = 125°C
$R_{DS(on)}$	V_{GS} = 10 V, $I_D = 0.5 \cdot I_{D25}$, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			0.4	Ω

Features
- International standard packages
- Low $R_{DS (on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect
- Fast intrinsic Rectifier

Applications
- DC-DC converters
- Uninterruptible Power Supplies (UPS)
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls
- Low voltage relays

Advantages
- Easy to mount with 1 screw (TO-247) (isolated mounting screw hole)
- Space savings
- High power density

IXYS reserves the right to change limits, test conditions, and dimensions.

91524D (10/95)

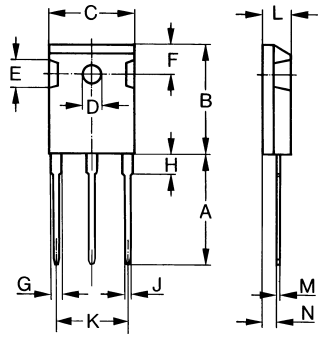
IXFH 13N50

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
g_{fs}	V_{DS} = 10 V; I_D = 0.5 I_{D25}, pulse test	7.5	9.0		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		2800		pF
C_{oss}			300		pF
C_{rss}			70		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 • I_{D25}, R_G = 4.7 Ω (External)		18	30	ns
t_r			27	40	ns
$t_{d(off)}$			76	100	ns
t_f			32	60	ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 • I_{D25}		110	120	nC
Q_{gs}			15	25	nC
Q_{gd}			40	50	nC
R_{thJC}				0.7	K/W
R_{thCK}			0.25		K/W

Source-Drain Diode

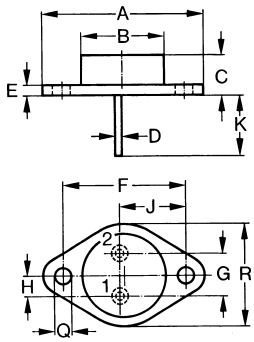
Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
I_S	V_{GS} = 0 V			13	A
I_{SM}	Repetitive; pulse width limited by T_{JM}			52	A
V_{SD}	$I_F = I_S$, V_{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %			1.5	V
t_{rr}	$I_F = I_S$, -di/dt = 100 A/µs, V_R = 100 V; T_J = 25°C			250	ns
	T_J = 125°C			350	ns
Q_{RM}	T_J = 25°C		0.6		µC
	T_J = 125°C		1.25		µC
I_{RM}	T_J = 25°C		9		A
	T_J = 125°C		15		A

TO-247 AD (IXFH) Outline



Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102

TO-204 AA (IXFM) Outline



Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	38.61	39.12	1.520	1.540
B	19.43	19.94	-	0.785
C	6.40	9.14	0.252	0.360
D	0.97	1.09	0.038	0.043
E	1.53	2.92	0.060	0.115
F	30.15	BSC	1.187	BSC
G	10.67	11.17	0.420	0.440
H	5.21	5.71	0.205	0.225
J	16.64	17.14	0.655	0.675
K	11.18	12.19	0.440	0.480
Q	3.84	4.19	0.151	0.165
R	25.16	25.90	0.991	1.020

Fig. 1 Output Characteristics

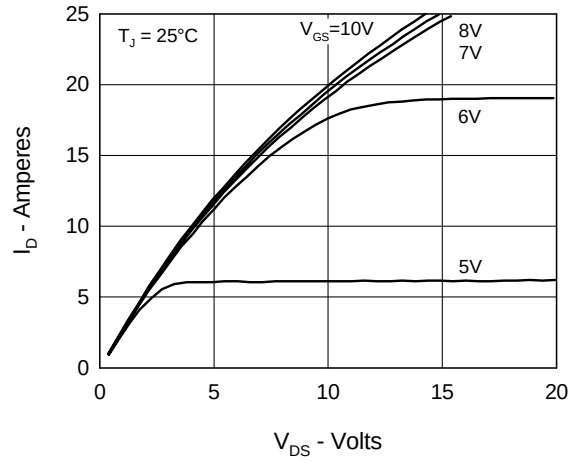


Fig. 2 Input Admittance

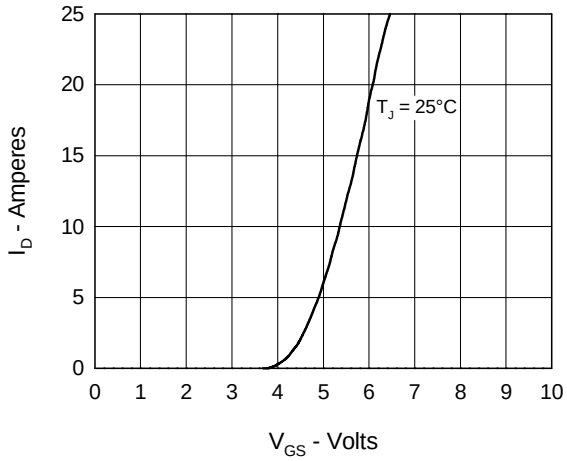


Fig. 3 $R_{DS(on)}$ vs. Drain Current

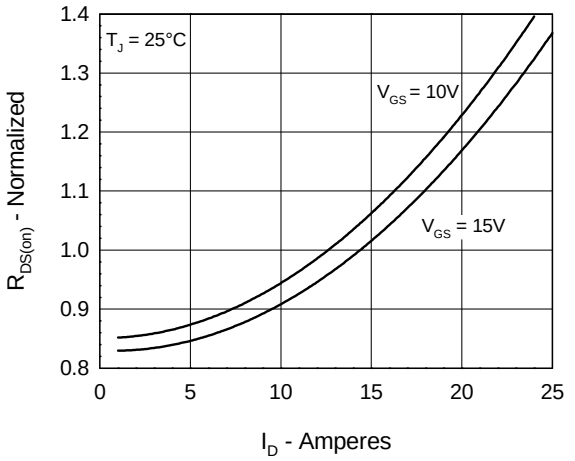


Fig. 4 Temperature Dependence of Drain to Source Resistance

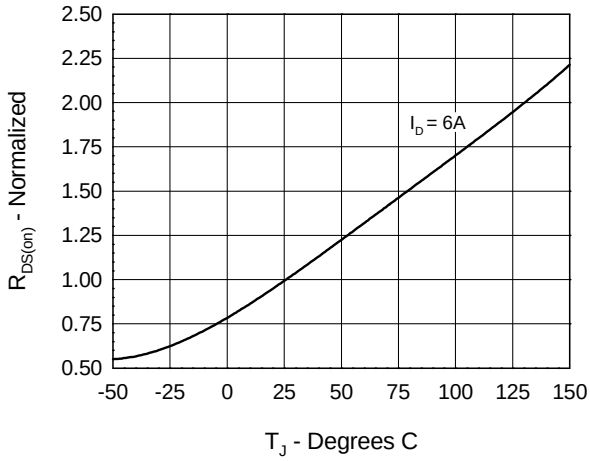


Fig. 5 Drain Current vs. Case Temperature

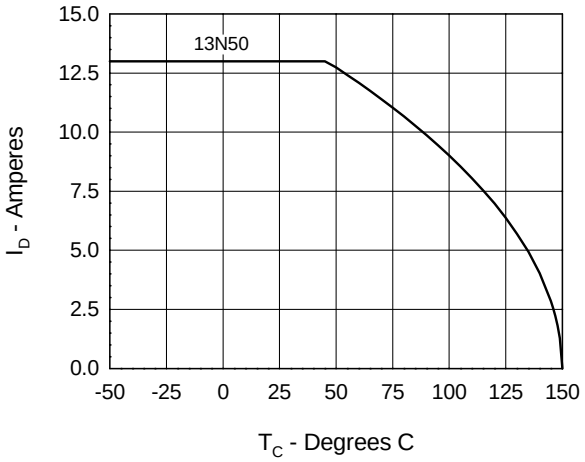
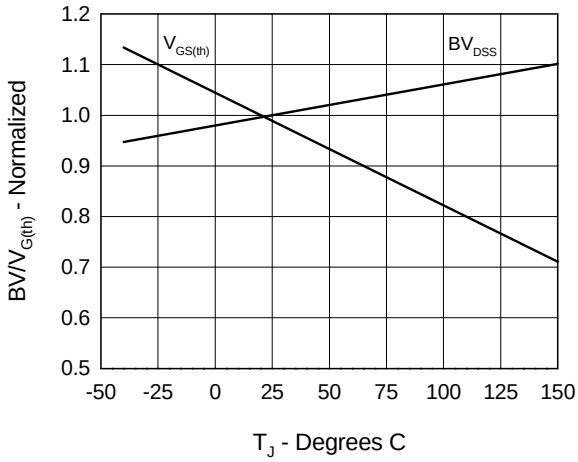


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage



IXFH 13N50

Fig.7 Gate Charge Characteristic Curve

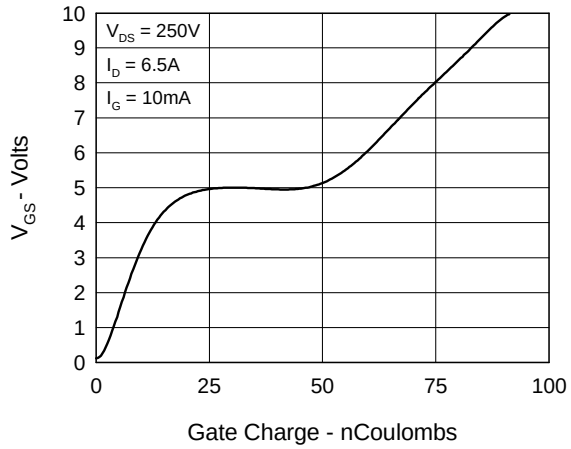


Fig.8 Forward Bias Safe Operating Area

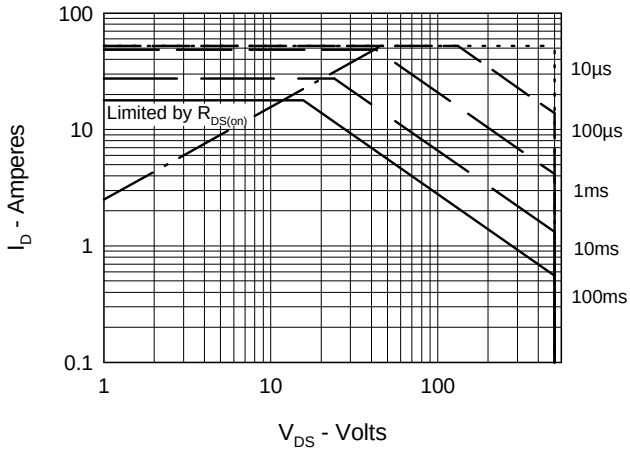


Fig.9 Capacitance Curves

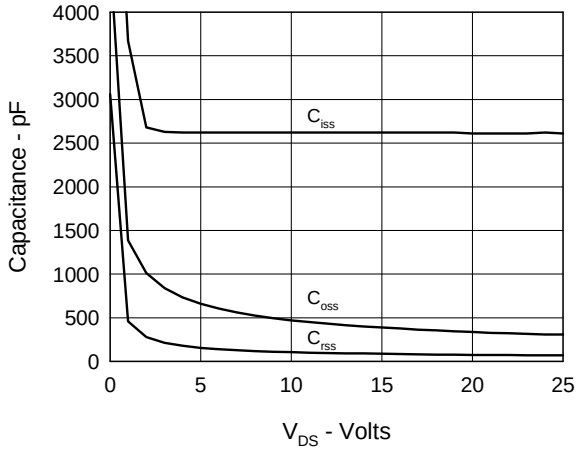


Fig.10 Source Current vs. Source to Drain Voltage

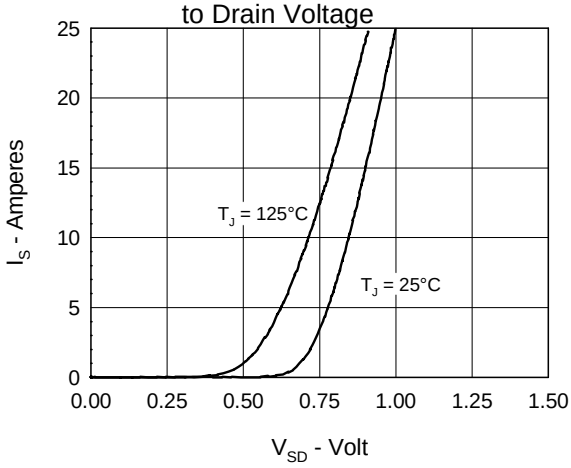


Fig.11 Transient Thermal Impedance